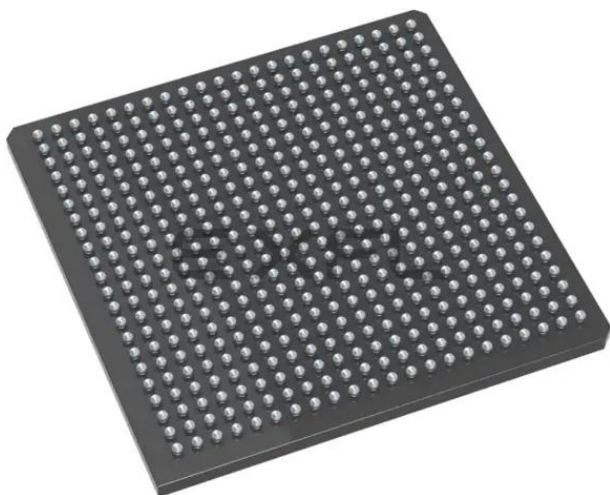




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	360
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (27X27)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-1fg484m

Logic Module Design

The SX-A family architecture is described as a “sea-of-modules” architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX-A family provides two types of logic modules: the register cell (R-cell) and the combinatorial cell (C-cell).

The R-cell contains a flip-flop featuring asynchronous clear, asynchronous preset, and clock enable, using the S0 and S1 lines control signals (Figure 1-2). The R-cell registers feature programmable clock polarity selectable on a register-by-register basis. This provides additional flexibility while allowing mapping of synthesized functions into the SX-A FPGA. The clock source for the R-cell can be chosen from either the hardwired clock, the routed clocks, or internal logic.

The C-cell implements a range of combinatorial functions of up to five inputs (Figure 1-3). Inclusion of the DB input and its associated inverter function allows up to 4,000

different combinatorial functions to be implemented in a single module. An example of the flexibility enabled by the inversion capability is the ability to integrate a 3-input exclusive-OR function into a single C-cell. This facilitates construction of 9-bit parity-tree functions with 1.9 ns propagation delays.

Module Organization

All C-cell and R-cell logic modules are arranged into horizontal banks called Clusters. There are two types of Clusters: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

Clusters are grouped together into SuperClusters (Figure 1-4 on page 1-3). SuperCluster 1 is a two-wide grouping of Type 1 Clusters. SuperCluster 2 is a two-wide group containing one Type 1 Cluster and one Type 2 Cluster. SX-A devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.

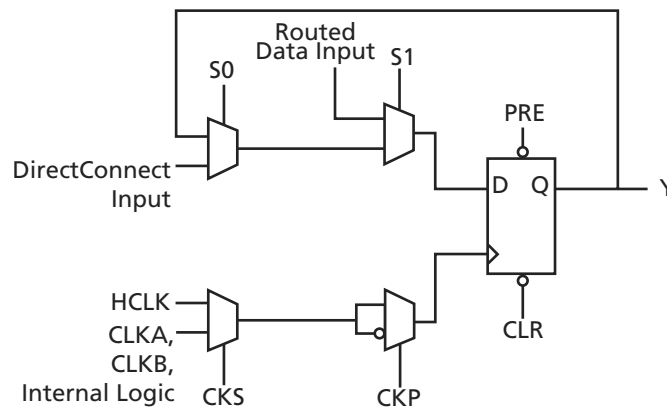


Figure 1-2 • R-Cell

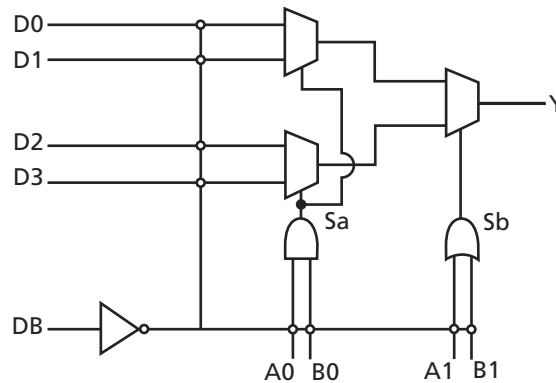


Figure 1-3 • C-Cell

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 • JTAG Instruction Code

Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 • JTAG Instruction Code

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 μ	0	8, 9	40B4, 42B4
		1	A, B	40B4, 42B4
A54SX16A	0.22 μ	0	9	40B8, 42B8
		1	B	40B8, 42B8
	0.25 μ	1	B	22B8
A54SX32A	0.2 2 μ	0	9	40BD, 42BD
		1	B	40BD, 42BD
	0.25 μ	1	B	22BD
A54SX72A	0.22 μ	0	9	40B2, 42B2
		1	B	40B2, 42B2
	0.25 μ	1	B	22B2

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the

PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a $70\ \Omega$ series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The $70\ \Omega$ series termination is used to prevent data transmission corruption during probing and reading back the checksum.

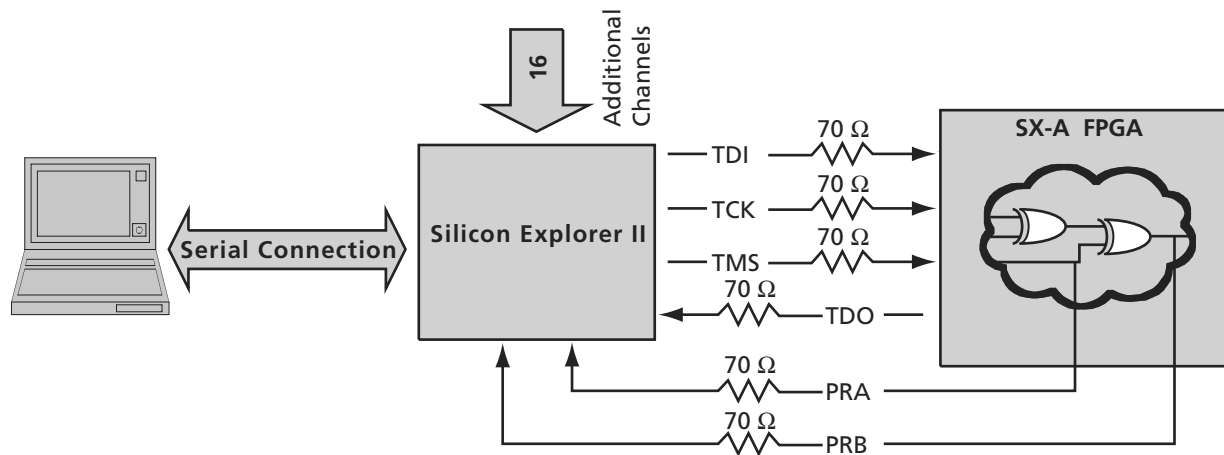


Figure 1-13 • Probe Setup

Pin Description

CLKA/B, I/O **Clock A and B**

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O **Quadrant Clock A, B, C, and D**

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND **Ground**

Low supply voltage.

HCLK **Dedicated (Hardwired) Array Clock**

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC **No Connection**

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O **Probe A/B**

The Probe pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O **Test Clock**

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user I/O when checksum is complete.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O **Boundary Scan Reset Pin**

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CC} **Supply Voltage**

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CC} power pins in the device should be connected.

V_{CCA} **Supply Voltage**

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Electrical Specifications

Table 2-5 • 3.3 V LVTTTL and 5 V TTL Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −1 mA)	0.9 V _{CCI}		0.9 V _{CCI}		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −8 mA)	2.4		2.4		V
V _{OL}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)	0.4		0.4		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 12 mA)	0.4		0.4		V
V _{IL}	Input Low Voltage		0.8		0.8		V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		−10	10	−10	10	μA
I _{OZ}	Tristate Output Leakage Current		−10	10	−10	10	μA
t _R , t _F	Input Transition Time t _R , t _F		10		10		ns
C _{IO}	I/O Capacitance		10		10		pF
I _{CC}	Standby Current		10		20		mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

Table 2-6 • 2.5 V LVCMOS2 Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -100 μA)	2.1		2.1		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -1 mA)	2.0		2.0		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -2 mA)	1.7		1.7		V
V _{OL}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 100 μA)	0.2		0.2		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)	0.4		0.4		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 2 mA)	0.7		0.7		V
V _{IL}	Input Low Voltage, V _{OUT} ≤ V _{VOL(max)}		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, V _{OUT} ≥ V _{VOH(min)}		1.7	5.75	1.7	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current, V _{OUT} = V _{CCI} or GND		-10	10	-10	10	μA
t _R , t _F	Input Transition Time t _R , t _F		10		10		ns
C _{IO}	I/O Capacitance		10		10		pF
I _{CC}	Standby Current		10		20		mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

Guidelines for Estimating Power

The following guidelines are meant to represent worst-case scenarios; they can be generally used to predict the upper limits of power dissipation:

Logic Modules (m) = 20% of modules

Inputs Switching (n) = Number inputs/4

Outputs Switching (p) = Number of outputs/4

CLKA Loads (q1) = 20% of R-cells

CLKB Loads (q2) = 20% of R-cells

Load Capacitance (CL) = 35 pF

Average Logic Module Switching Rate (fm) = f/10

Average Input Switching Rate (fn) = f/5

Average Output Switching Rate (fp) = f/10

Average CLKA Rate (fq1) = f/2

Average CLKB Rate (fq2) = f/2

Average HCLK Rate (fs1) = f

HCLK loads (s1) = 20% of R-cells

To assist customers in estimating the power dissipations of their designs, Actel has published the *eX*, *SX-A* and *RT54SX-S* *Power Calculator* worksheet.

Table 2-16 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.3		1.5		1.7		2.6	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.1		1.3		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.5		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		1.9	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.2		1.3		1.6		2.2	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.8		0.9		1.1		1.5	ns

Table 2-28 • A54SX32A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.9		1.1		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays³												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-30 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.6	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.4		2.7		3.2		4.5	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.3		2.7		3.1		3.6		5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.5		2.9		3.4		4.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.1	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.9		1.0		1.2		1.4		1.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.4		1.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-34 • A54SX32A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.1		2.4		2.8		3.2		4.5		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.1		2.4		2.8		3.2		4.5		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.8		3.2		3.6		4.2		5.9		ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032		ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052		ns/pF
5 V TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	1.9		2.2		2.5		2.9		4.1		ns
t _{DHL}	Data-to-Pad High to Low	2.5		2.9		3.3		3.9		5.4		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	6.6		7.6		8.6		10.1		14.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.5		2.9		4.1		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.3		3.9		5.4		ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031		ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HLH|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HLH|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-35 • A54SX72A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ²												
t _{PD}	Internal Array Module	1.0		1.1		1.3		1.5		2.0		ns
Predicted Routing Delays ³												
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.3		0.4		0.5		0.7		ns
t _{RD2}	FO = 2 Routing Delay	0.4		0.5		0.6		0.7		1		ns
t _{RD3}	FO = 3 Routing Delay	0.5		0.7		0.8		0.9		1.3		ns
t _{RD4}	FO = 4 Routing Delay	0.7		0.9		1		1.1		1.5		ns
t _{RD8}	FO = 8 Routing Delay	1.2		1.5		1.7		2.1		2.9		ns
t _{RD12}	FO = 12 Routing Delay	1.7		2.2		2.5		3		4.2		ns
R-Cell Timing												
t _{RCO}	Sequential Clock-to-Q	0.7		0.8		0.9		1.1		1.5		ns
t _{CLR}	Asynchronous Clear-to-Q	0.6		0.7		0.7		0.9		1.2		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.8		1.0		1.4		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.7		2.0		2.8		ns
t _{RECASYN}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Hold Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Minimum Pulse Width	1.5		1.7		2.0		2.3		3.2		ns
Input Module Propagation Delays												
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.6		0.7		0.8		0.9		1.3		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	0.8		1.0		1.1		1.3		1.7		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.6		0.7		0.7		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7		0.8		0.9		1.0		1.4		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.7		0.7		0.8		1.0		1.4		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.0		1.2		1.3		1.5		2.1		ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-35 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.6		0.7		0.8		1.1	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.8		0.9		1.0		1.2		1.6	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
Input Module Predicted Routing Delays³												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.7	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.6		0.7		1	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.7		0.8		0.9		1.3	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.9		1		1.1		1.5	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.5		1.7		2.1		2.9	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.2		2.5		3		4.2	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-37 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		1.9		2.1		2.5		3.8	ns
t _{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t _{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f _{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.8	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.3		3.7		4.3		6.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		4.0		5.6	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		3.1		3.6		4.1		4.8		6.7	ns
t _{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3		4.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.9		2.1		2.4		2.8		3.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.9		2.1		2.4		2.8		3.9	ns
Quadrant Array Clock Networks												
t _{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.3		1.5		1.7		1.9		2.7	ns
t _{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.5		1.7		2		2.8	ns
t _{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.5		1.7		1.9		2.2		3.1	ns
t _{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.8		2		2.3		3.2	ns

Note: *All –3 speed grades have been discontinued.

Table 2-38 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.5	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All -3 speed grades have been discontinued.

176-Pin TQFP		176-Pin TQFP		176-Pin TQFP		176-Pin TQFP	
Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function
1	GND	37	I/O	73	I/O	109	V _{CCA}
2	TDI, I/O	38	I/O	74	I/O	110	GND
3	I/O	39	I/O	75	I/O	111	I/O
4	I/O	40	I/O	76	I/O	112	I/O
5	I/O	41	I/O	77	I/O	113	I/O
6	I/O	42	I/O	78	I/O	114	I/O
7	I/O	43	I/O	79	I/O	115	I/O
8	I/O	44	GND	80	I/O	116	I/O
9	I/O	45	I/O	81	I/O	117	I/O
10	TMS	46	I/O	82	V _{CCI}	118	I/O
11	V _{CCI}	47	I/O	83	I/O	119	I/O
12	I/O	48	I/O	84	I/O	120	I/O
13	I/O	49	I/O	85	I/O	121	I/O
14	I/O	50	I/O	86	I/O	122	V _{CCA}
15	I/O	51	I/O	87	TDO, I/O	123	GND
16	I/O	52	V _{CCI}	88	I/O	124	V _{CCI}
17	I/O	53	I/O	89	GND	125	I/O
18	I/O	54	I/O	90	I/O	126	I/O
19	I/O	55	I/O	91	I/O	127	I/O
20	I/O	56	I/O	92	I/O	128	I/O
21	GND	57	I/O	93	I/O	129	I/O
22	V _{CCA}	58	I/O	94	I/O	130	I/O
23	GND	59	I/O	95	I/O	131	I/O
24	I/O	60	I/O	96	I/O	132	I/O
25	TRST, I/O	61	I/O	97	I/O	133	GND
26	I/O	62	I/O	98	V _{CCA}	134	I/O
27	I/O	63	I/O	99	V _{CCI}	135	I/O
28	I/O	64	PRB, I/O	100	I/O	136	I/O
29	I/O	65	GND	101	I/O	137	I/O
30	I/O	66	V _{CCA}	102	I/O	138	I/O
31	I/O	67	NC	103	I/O	139	I/O
32	V _{CCI}	68	I/O	104	I/O	140	V _{CCI}
33	V _{CCA}	69	HCLK	105	I/O	141	I/O
34	I/O	70	I/O	106	I/O	142	I/O
35	I/O	71	I/O	107	I/O	143	I/O
36	I/O	72	I/O	108	GND	144	I/O

144-Pin FBGA

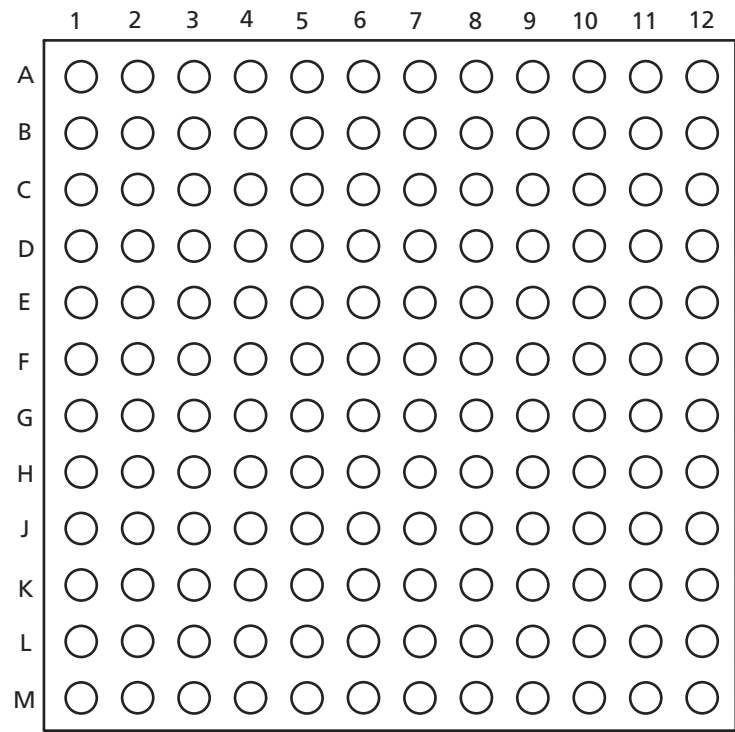


Figure 3-6 • 144-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
P15	I/O	I/O	I/O
P16	I/O	I/O	I/O
R1	I/O	I/O	I/O
R2	GND	GND	GND
R3	I/O	I/O	I/O
R4	NC	I/O	I/O
R5	I/O	I/O	I/O
R6	I/O	I/O	I/O
R7	I/O	I/O	I/O
R8	I/O	I/O	I/O
R9	HCLK	HCLK	HCLK
R10	I/O	I/O	QCLKB
R11	I/O	I/O	I/O
R12	I/O	I/O	I/O
R13	I/O	I/O	I/O
R14	I/O	I/O	I/O
R15	GND	GND	GND
R16	GND	GND	GND
T1	GND	GND	GND
T2	I/O	I/O	I/O
T3	I/O	I/O	I/O
T4	NC	I/O	I/O
T5	I/O	I/O	I/O
T6	I/O	I/O	I/O
T7	I/O	I/O	I/O
T8	I/O	I/O	I/O
T9	V _{CCA}	V _{CCA}	V _{CCA}
T10	I/O	I/O	I/O
T11	I/O	I/O	I/O
T12	NC	I/O	I/O
T13	I/O	I/O	I/O
T14	I/O	I/O	I/O
T15	TDO, I/O	TDO, I/O	TDO, I/O
T16	GND	GND	GND

484-Pin FBGA

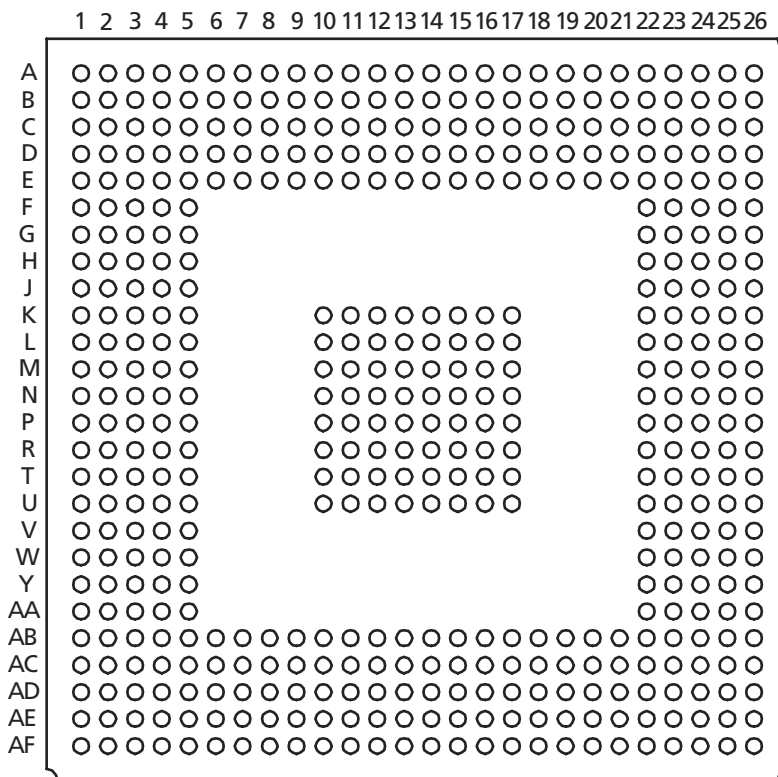


Figure 3-8 • 484-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
C19	I/O	I/O
C20	V _{CCI}	V _{CCI}
C21	I/O	I/O
C22	I/O	I/O
C23	I/O	I/O
C24	I/O	I/O
C25	NC*	I/O
C26	NC*	I/O
D1	NC*	I/O
D2	TMS	TMS
D3	I/O	I/O
D4	V _{CCI}	V _{CCI}
D5	NC*	I/O
D6	TCK, I/O	TCK, I/O
D7	I/O	I/O
D8	I/O	I/O
D9	I/O	I/O
D10	I/O	I/O
D11	I/O	I/O
D12	I/O	QCLKC
D13	I/O	I/O
D14	I/O	I/O
D15	I/O	I/O
D16	I/O	I/O
D17	I/O	I/O
D18	I/O	I/O
D19	I/O	I/O
D20	I/O	I/O
D21	V _{CCI}	V _{CCI}
D22	GND	GND
D23	I/O	I/O
D24	I/O	I/O
D25	NC*	I/O
D26	NC*	I/O
E1	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
E2	NC*	I/O
E3	I/O	I/O
E4	I/O	I/O
E5	GND	GND
E6	TDI, IO	TDI, IO
E7	I/O	I/O
E8	I/O	I/O
E9	I/O	I/O
E10	I/O	I/O
E11	I/O	I/O
E12	I/O	I/O
E13	V _{CCA}	V _{CCA}
E14	CLKB	CLKB
E15	I/O	I/O
E16	I/O	I/O
E17	I/O	I/O
E18	I/O	I/O
E19	I/O	I/O
E20	I/O	I/O
E21	I/O	I/O
E22	I/O	I/O
E23	I/O	I/O
E24	I/O	I/O
E25	V _{CCI}	V _{CCI}
E26	GND	GND
F1	V _{CCI}	V _{CCI}
F2	NC*	I/O
F3	NC*	I/O
F4	I/O	I/O
F5	I/O	I/O
F22	I/O	I/O
F23	I/O	I/O
F24	I/O	I/O
F25	I/O	I/O
F26	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
G1	NC*	I/O
G2	NC*	I/O
G3	NC*	I/O
G4	I/O	I/O
G5	I/O	I/O
G22	I/O	I/O
G23	V _{CCA}	V _{CCA}
G24	I/O	I/O
G25	NC*	I/O
G26	NC*	I/O
H1	NC*	I/O
H2	NC*	I/O
H3	I/O	I/O
H4	I/O	I/O
H5	I/O	I/O
H22	I/O	I/O
H23	I/O	I/O
H24	I/O	I/O
H25	NC*	I/O
H26	NC*	I/O
J1	NC*	I/O
J2	NC*	I/O
J3	I/O	I/O
J4	I/O	I/O
J5	I/O	I/O
J22	I/O	I/O
J23	I/O	I/O
J24	I/O	I/O
J25	V _{CCI}	V _{CCI}
J26	NC*	I/O
K1	I/O	I/O
K2	V _{CCI}	V _{CCI}
K3	I/O	I/O
K4	I/O	I/O
K5	V _{CCA}	V _{CCA}

Note: *These pins must be left floating on the A54SX32A device.

